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**Call For Participation:**

IEEE 6th International Workshop on  
Microprocessor Test & Verification (MTV 2005)  
Hyatt Town Lake Hotel, Austin, Texas, USA  
November 3- 4, 2005

Web Site: <http://mtv.ece.ucsb.edu/MTV/>

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**Deadlines:**

- Advance Workshop Reservation: October 23, 2005, 5pm USA EST
- Advance Hotel Registration: October 12, 2005 Rate \$149

MTV'05 Workshop Registration and Hotel Reservation are available at

<http://mtv.ece.ucsb.edu/MTV/>

Hyatt Town Lake Hotel, 208 Barton Springs Road, Austin, Texas 78704  
Reservation Number: 1 (800) 233-1234 or (512) 477-1234

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# **Final Program**

## **MTV 2005**

### **Wednesday, November 2, 2005**

**7-9pm: Pre-event Reception at the Hyatt, Town Lake, Austin**

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### **Thursday, November 3, 2005**

**7:30-8:30am: Continental Breakfast**

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**8:30-8:40am: Opening Introduction, Magdy Abadir, General Chair**

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**8:40-10:45am**

**Session A: Architecture Description Languages,  
Organizer: Eli Almog, IBM,  
Session Chair: Magdy Abadir, Freescale Semiconductor**

**A.1** *A Study of Architecture Description Languages from a Model-based Perspective*

Prof. Wei Qin, Boston University, Sharad Malik, Princeton University.

**A.2** *An Introduction to the Plasma Language*, Brian Kahne, Pete Wilson, Freescale Semiconductor, Aseem Gupta and Nikil Dutt, University of California at Irvine.

**A.3** *Embedded Processor Design and SW Tool Generation Using LISA*, Andreas Hoffmann, CoWare.

**A.4** *Verifying Configurable ISAs Described in Tensilica's Instruction Extension (TIE) Language*, Dhanendra Jani, Tensilica

**A.5** *Processor Architecture Description Language for Test Generation*, Eli Almog, IBM.

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**10:45am-11:00am: Coffee Break**

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**11am – 11:50am**

**Session B: SAT Applications**

**Session Chair: TBD**

**B.1** *Bounded Invariant Checking of Partial Implementations Using a Structural SAT-Solver*, Marc Herbstritt and Bernd Becker, Albert-Ludwigs-University of Freiburg, Freiburg, Germany

**B.2** *PaMira – a Parallel SAT Solver with Knowledge Sharing*, Tobias Schubert, Matthew Lewis, and Bernd Becker, Albert-Ludwigs-University of Freiburg, Freiburg, Germany

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**11:50am-1pm: Lunch Break**

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**1pm – 2:40pm**

**Session C: Debug and Diagnosis**

**Session Chair: Li-C Wang, UC-Santa Barbara**

**C.1** *Diagnosing faulty functional units in processors by using automatically generated test sets*, P. Bernardi, E. Sanchez, M. Schillaci, G. Squillero, M. Sonza Reorda  
Dipartimento di Automatica e Informatica, Politecnico di Torino, Italy

**C.2** *Post-Verification Debugging of Hierarchical Designs*, Moayad Fahim Ali, Sean Safarpour, Andreas Veneris, University of Toronto, Magdy S. Abadir, Freescale Semiconductor, and Rolf Drechsler, University of Bremen, Germany

**C.3** *An Investigation of Excitation Balance and Additional Mandatory Conditions for the Diagnosis of Fortuitously Detected Defects*, Jennifer Lynn Dworak, Brown University

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**C.4 Exploiting an I-IP for both Test and Silicon Debug of Microprocessor Cores**, P. Bernardi, M. Grosso, M. Rebaudengo, M. Sonza Reorda, Politecnico di Torino, Dipartimento di Automatica e Informatica, Torino, Italy

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**2:40 – 3pm: Coffee Break**

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**3:00 – 5:05pm**

**Session D: Functional Test Generation, Circuit Marginality and Speed Binning**

**Session Chair: TBD**

**D.1 Is IDDQ Test of Microprocessors Feasible?** Bin Xue and D. M. H. Walker, Texas A&M University

**D.2 Improved methods for Circuit Marginality, Speed Path & Manufacturing Defect Detection**, Greg Czajkowski, Dave LaFollette, and Paul R. Zehr, Intel Corporation

**D.3 System Level Verification using Hierarchical Test Case Synthesis**, Adnan Hamid, Breker Verification Systems

**D.4 The Generator Construction Set -- A New Approach to Random Test Generators**, Melanie D. Typaldos and Rebecca Cavanaugh, Obsidian Software Inc.

**D.5 Simulation Data Mining for Functional TPG**, Charles H-P Wen and Li-C. Wang, UC-Santa Barbara

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**5:30-9 pm: Dinner and Social Event**

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**November 4, Friday**

**7:30 – 8:30am: Continental Breakfast**

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**8:30am – 10:10am**

**Session E: IP and Processor Validation**

**Session Chair: TBD**

**E.1 Automated Extraction of Structural Information from SystemC based IP for Validation**, David Berner, Institut de Recherche en Informatique et Systèmes Avancés, France  
Hiren D. Patel, Deepak A. Mathaikutty, and Sandeep K. Shukla, Virginia Polytechnic and State University

**E.2** *Pre-Silicon Validation of IPF Memory Ordering for Multi-Core Processors*, Soohong Kim, Intel Corporation

**E.3** *Automatic Generation of High Performance Embedded Memory Models for PowerPC Microprocessors*, Jayanta Bhadra, Magdy S. Abadir, David Burgess, and Ekaterina Trofimova, Freescale Semiconductor

**E.4** *Language-driven Validation of Pipelined Processors using Satisfiability Solvers*  
Prabhat Mishra, Heon-Mo Koo, and Zhuo Huang, University of Florida, Gainesville, Florida

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**10:10am – 10:20am: Coffee Break**

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**10:20am – 12noon**

**Session F: High-level ATPG and Verification**  
**Session Chair: Magdy Abadir, Freescale Semiconductor**

**F.1** *On PSL Properties Re-use in SoC Design Flow Based on Transaction Level Modeling*, Nicola Bombieri, Andrea Fedeli, STMicroelectronics, and Franco Fummi, University of Verona

**F.2** *A Pseudo-Deterministic Functional ATPG based on EFSM Traversing*, G. Di Guglielmo F. Fummi C. Marconcini G. Pravadelli, Dipartimento di Informatica - Università di Verona, Italy

**F.3** *Search-space optimizations for high-speed ATPG*, Jorge Campos and Hussain Al-Asaad, University of California, at Davis

**F.4** *HW/SW Co-Verification of a RISC CPU using Bounded Model Checking*, Daniel Grosse, Ulrich Kuehne, Rolf Drechsler, University of Bremen

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**12:00 – 1:15pm: Lunch Break**

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**1:15 – 2:30pm**

**Session G: Invited Presentations**  
**Session Chair: Madhusudan S Ponnada, Intel Corporation**

**G.1** *3D circuits and its test challenges*, T. M. Mak, Intel Corporation

**G.2** *Equivalence Checking -- An Industry Perspective*, Kei-Yong Khoo, Cadence Design Systems, Inc.

**G.3** *A TDM Test Scheduling Method for Network-on-Chip Systems*, Mark Nolen, Rabi Mahapatra and Ray Mercer, Texas A&M University

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**2:30pm-3:45pm**

**Special session H: Advanced Industrial Developments in Test**

**Organizer: Al Crouch, Inovys**

**Session Chair: TBD**

Speaker: Jason Doege, Cadence

Speaker: Bill Bruce, Silicon Aid

Speaker: Al Crouch, Inovys

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**3:45-4:00pm Coffee Break**

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**4:00 – 5:15pm**

**Special session I: Sequential Equivalence Checking**

**Organizer/Session Chair: Anmol Mathur, Calypto Design Systems**

**I.1** Using *sequential equivalence checking in a microprocessor design flow*, Brian Kahne and Magdy Abadir, Freescale Semiconductor

**I.2** *Sequential Equivalence Checking of RTL Models*, Gagan Hasteer, Venkat Krishnaswamy and Nikhil Sharma, Calypto Design Systems

**I.3** *Seq-SAT - An Efficient Sequential Circuit SAT Solver and Its Application to Sequential Equivalence Checking*, Feng Lu, K.-T. Cheng and L.C Wang, Department of ECE, University of California at Santa Barbara

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**5:15pm --- Closing Remarks (committee meeting)**